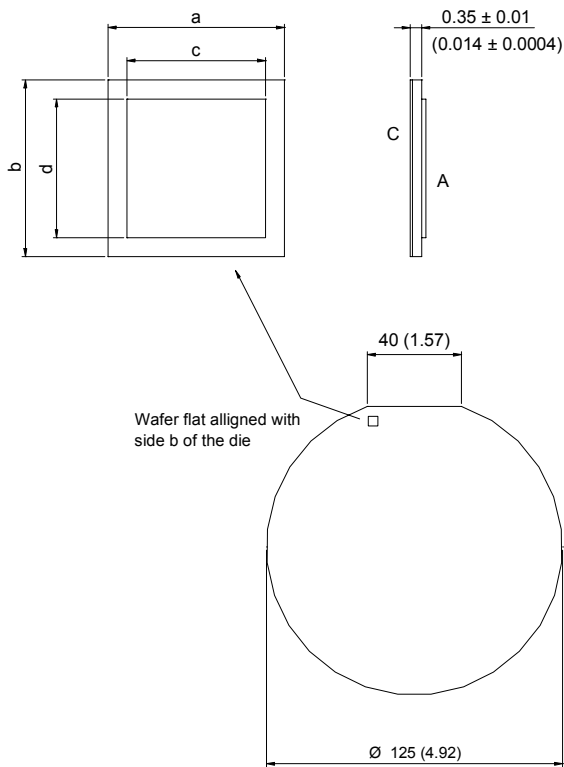


Fred Die in Wafer Form



NOTES:

1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
2. CONTROLLING DIMENSION (INCH):
3. DIMENSIONS AND TOLERANCES:
 - a = 4.064 ± 0.05 (0.160 ± 0.002)
 - b = 4.064 ± 0.05 (0.160 ± 0.002)
 - c = 3.404 ± 0.003 (0.134 ± 0.0001)
 - d = 3.404 ± 0.003 (0.134 ± 0.0001)
4. LETTER DESIGNATION:
 - A = Anode (Top Metal)
 - C = Cathode (Back Metal)
5. SAWING:
 - Recommended Blade
 - SEMITEC S1025 QS00 Blade
6. MINIMUM ORDER QUANTITY:
 - 500 die

NOT TO SCALE

Reference IR Packaged Part: 30ETH06/ 30EPH06 Series

Electrical Characteristics (Wafer Form)

Parameters	Units	Test Conditions
V _{FM} Maximum Forward Voltage	2.3 V	T _J = 25°C, I _F = 30 A
V _{RRM} Mimunum Reverse Breakdown Voltage	600 V	T _J = 25°C, I _{RRM} = 200 μA
I _{RM} Max. Reverse Leakage Current	100μA	T _J = 25°C, V _{RRM} = 600 V
t _{rr} Typ. Reverse Recovery Time	20 ns	I _F = 1A, di/dt = 100A/μs, V _R = 30 V

Mechanical Data

Nominal Back Metal Composition, Thickness	Cr - Ni - Ag (1 KA - 2 KA - 3 KA)
Nominal Front Metal Composition, Thickness	99% Al, 1% Si (3 microns)
Chip Dimensions	0.160" x 0.160" (see drawing)
Reject Ink Dot Size	0.25 mm diameter minimum
Recommended Storage Environment	Storage in original container, in dessicated nitrogen, with no contamination

Ordering Information Table

Device Code	
1 - Fred Die	
2 - Chip Dimension in Mils: 160 = 160x160 square	
3 - Process: H = HyperFast	
4 - Voltage code Vrrm (*100) eg: 06 = 600V	
5 - Chip surface metallization: A = Aluminium (anode), Silver (cathode)	
6 - Wafer diameter in inches	
7 - Packaging: B = Inked Probed Unsawn Wafer (Wafer in box)	